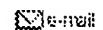


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Allebach, J.; Ping Wah Wong

[Image Processing, 1996. Proceedings., International Conference on](#)

Volume: 3 16-19 Sep 1996

Page(s): 707-710 vol.3

Digital Object Identifier 10.1109/ICIP.1996.560768

Summary: We present a new method for digitally interpolating images to higher resolution. It consists of two phases: rendering and correction. The rendering phase is edge-directed. From the image data, we generate a high resolution edge map by[AbstractPlus](#) | Full Text: [PDF](#) [IEEE CNF](#)**2. A minimax method for function interpolation using an SLI structure**

Agar, A.U.; Allebach, J.P.

[Image Processing, 1997. Proceedings., International Conference on](#)

Volume: 1 26-29 Oct 1997

Page(s): 671-674 vol.1

Digital Object Identifier 10.1109/ICIP.1997.648002

Summary: We derive a closed form solution to the problem of finding an optimal grid for sequential linear interpolation (SLI) of a 3-D function. The criterion of optimality is to minimize the maximum absolute interpolation error. The approach we take.....[AbstractPlus](#) | Full Text: [PDF](#) [IEEE CNF](#)[View: 1-2](#) | [View Search Results](#)[Help](#) [Contact Us](#) [Privacy & Terms](#)

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